4	Application No.	Applicant(s)	Applicant(s)	
Notice of Allowability	09/769,080	HSU ET AL.		
	Examiner	Art Unit		
	Alonzo Chambliss	2827	·	
The MAILING DATE of this communication at All claims being allowable, PROSECUTION ON THE MERITS herewith (or previously mailed), a Notice of Allowance (PTOL-NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT of the Office or upon petition by the applicant. See 37 CFR 1.3	TS (OR REMAINS) CLOSED in 85) or other appropriate communication is a	this application. If not inc	luded	
 This communication is responsive to <u>amendment A filed</u> The allowed claim(s) is/are <u>1-24 and 33-42</u>. The drawings filed on are accepted by the Exam Acknowledgment is made of a claim for foreign priority of a) All Bome* C) None of the: Certified copies of the priority documents have 	<u>d on 8/29/02 and interview sum</u> iner. under 35 U.S.C. § 119(a)-(d) or			
2. Certified copies of the priority documents ha	ave been received in Application	ı No		
 3. Copies of the certified copies of the priority International Bureau (PCT Rule 17.2(a)). * Certified copies not received: 5. Acknowledgment is made of a claim for domestic priority (a) The translation of the foreign language provisiona 	documents have been received under 35 U.S.C. § 119(e) (to a	in this national stage appl provisional application).	ication from the	
6. Acknowledgment is made of a claim for domestic priority	under 35 U.S.C. §§ 120 and/or	121		
Applicant has THREE MONTHS FROM THE "MAILING DATE" below. Failure to timely comply will result in ABANDONMENT of the complex o	on this application. This THRE	E-MONTH PERIOD IS NO	OT EXTENDABLE	
 (a) ☐ including changes required by the Notice of Draftsport 1) ☐ hereto or 2) ☒ to Paper No. 4. 				
(b) ☐ including changes required by the proposed drawing Examiner.				
(c) \square including changes required by the attached Examine	er's Amendment / Comment or i	n the Office action of Pape	er No	
Identifying indicia such as the application number (see 37 CFR of each sheet. The drawings should be filed as a separate paper	4.04(-)) = 5			
9. DEPOSIT OF and/or INFORMATION about the departached Examiner's comment regarding REQUIREMENT FOR	osit of BIOLOGICAL MATER THE DEPOSIT OF BIOLOGICA	RIAL must be submitted. AL MATERIAL.	. Note the	
Attachment(s)				
 1 ☐ Notice of References Cited (PTO-892) 3 ☐ Notice of Draftperson's Patent Drawing Review (PTO-948) 5 ☐ Information Disclosure Statements (PTO-1449), Paper No	4⊠ Interview S 6⊠ Examiner's	nformal Patent Application Summary (PTO-413), Pape s Amendment/Comment s Statement of Reasons for	er No. <u>8</u> .	

Application/Control Number: 09/769,080

Art Unit: 2827

DETAILED ACTION

EXAMINER'S AMENDMENT

1. An examiner's amendment to the record appears below. Should the changes and/or additions be unacceptable to applicant, an amendment may be filed as provided by 37 CFR 1.312. To ensure consideration of such an amendment, it MUST be submitted no later than the payment of the issue fee.

Authorization for this examiner's amendment was given in a telephone interview with Christopher Palestro on behave of Paul J. Farrell on March 7, 2003.

The application has been amended as follow:

IN CLAIMS:

In claim 1, line 3, delete "on "and insert instead – in said at least one substrate by a photoresist having --;

In claim 1, line 4, after "irradiated on "insert - opposing surfaces of --;

In claim 1, line 5, after "circuit systems" insert – opposing surfaces of the at least one substrate --;

In claim 13, line 2, delete "on "and insert instead – in said at least one substrate by a photoresist having --;

In claim 13, line 3, after "irradiated on "insert - opposing surfaces of --;

In claim 13, line 4, after "circuit systems" insert – opposing surfaces of the at least one substrate --.

Allowable Subject Matter

3. The following is a statement of reasons for the indication of allowance subject matter: the prior art of record does not teach or suggest the combination of a substrate having aligned global alignment marks formed in the substrate by a photoresist having an alignment pattern irradiated on opposing surfaces of the substrate. First and second circuit systems on opposing surfaces of the substrate, wherein each circuit system are aligned via the global alignment marks.

Any inquiry concerning the communication or earlier communications from the examiner should be directed to Alonzo Chambliss whose telephone number is (703) 306-9143. The fax phone number for the Group is (703) 308-772 or 7724.

Any inquiry of a general nature or relating to the status of this application or proceeding should be directed to the group receptionist whose telephone number is (703) 308-7956.

DAVID L. TALBOTT

SUPERVISORY PRICER ELAVINER

TECHNOLOGY CENTER 2800

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AC/February 24, 2003